

Search Notes

Application/Control No.

10/594,282

Examiner

Sin J. Lee

Applicant(s)/Patent under
Reexamination

ISHII ET AL.

Art Unit

1795

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EIC STRUCTURE SEARCH	5/23/2009	SJL